

Product Change Notification: CAAN-02PELF720

Date:

10-Jun-2025

Product Category:

32-Bit Microcontrollers

Notification Subject:

CCB 6779 Final Notice: Qualification of ANAP as an additional assembly site for ATSAM3S8CA-AU, ATSAM3S8CA-AUR, ATSAM3SD8CA-AU and ATSAM3SD8CA-AUR catalog part numbers (CPN) available in 100L LQFP (14x14x1.4mm) package.

Affected CPNs:

CAAN-02PELF720_Affected_CPN_06102025.pdf CAAN-02PELF720_Affected_CPN_06102025.csv

PCN Status: Final Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of ANAP as an additional assembly site for ATSAM3S8CA-AU, ATSAM3S8CA-AUR, ATSAM3SD8CA-AU and ATSAM3SD8CA-AUR catalog part numbers (CPN) available in 100L LQFP (14x14x1.4mm) package.

Pre and Post Summary Changes:

	Pre Change	Post Change				
Assembly Site	ATX Semiconductor (Shanghai)Co. Ltd (ASSH)	ATX Semiconductor (Shanghai)Co. Ltd (ASSH)	Amkor Technology Philippine (P1/P2), INC. (ANAP)			
Wire Material	Au	Au	Au			
Die Attach Material	2288A	2288A	3230			

Molding Compound Material	CEL-9200THF	CEL-9200THF	G631HQ			
Lead-Frame Material	C7025	C7025	C194ESH			
Lead-Frame Paddle Size	240X240 mils	240X240 mils	315X315 mils			
Lead-Frame Design	ead-Frame Design See Pre and Post Change Comparison					
DAP Surface Prep	Double Ring Ag	Double Ring Ag	Double Ring Ag			

Impacts to Datasheet: None

Change Impact: None

Reason for Change: To improve on-time delivery performance by qualifying ANAP as an additional

assembly site.

Change Implementation Status: In Progress

Estimated First Ship Date: 30 June 2025 (date code: 2527)

Note Below EFSD: Note: Please be advised that after the estimated first ship date customers may

receive pre and post change parts.

Timetable Summary:

	January 2024				>	June 2025					
Work Week	01	02	03	04	05		23	24	25	26	27
Initial PCN Issue Date	X										
Qual Report Availability								X			
Final PCN Issue Date								X			
Estimated Implementation Date											X

Method to Identify Change: Traceability Code

Qualification Report: Please open the attachments included with this PCN labeled as

PCN # Qual Report.

Revision History: January 5, 2024: Issued initial notification.

June 6, 2025: Issued final notification. Attached the Qualification Report. Provided the estimated first ship date to be on June 30, 2025.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

PCN_CAAN-02PELF720_Pre and Post Change Summary.pdf PCN_CAAN-02PELF720 Qual_Report.pdf

Please contact your local **Microchip sales office** with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our <u>PCN</u> <u>home page</u> select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the <u>PCN FAQ</u> section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

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ATSAM3S8CA-AUR, ATSAM3SD8CA-AU and ATSAM3SD8CA-AUR catalog part numbers (CPN) available in 100L LQFP
(14x14x1.4mm) package.

Affected Catalog Part Numbers (CPN)

ATSAM3SD8CA-AUR

ATSAM3S8CA-AU

ATSAM3S8CA-AUR

ATSAM3SD8CA-AU

Date: Monday, June 9, 2025



QUALIFICATION REPORT SUMMARY RELIABILITY LABORATORY

PCN #: CAAN-02PELF720

Date: May 6, 2025

Qualification of ANAP as an additional assembly site for ATSAM3S8CA-AU, ATSAM3S8CA-AUR, ATSAM3SD8CA-AU and ATSAM3SD8CA-AUR catalog part numbers (CPN) available in 100L LQFP (14x14x1.4mm) package.



Purpose: Qualification of ANAP as an additional assembly site for ATSAM3S8CA-AU,

ATSAM3S8CA-AUR, ATSAM3SD8CA-AU and ATSAM3SD8CA-AUR catalog part

numbers (CPN) available in 100L LQFP (14x14x1.4mm) package.

CCB No.: 6779

	Assembly site	ANAP
	BD Number	BD-002073-01
	MP Code (MPC)	58U837H7XC01
	Part Number (CPN)	ATSAM3S8CA-AU
Misc.	MSL information	MSL3
	Assembly Shipping Media	Tray
	Base Quantity Multiple (BQM)	90/Tray
	Reliability Site	MPHIL
	Paddle size	315X315
	Material	C194ESH
	DAP Surface Prep	Double Ring Ag
	Treatment	Non-roughened
Lood France	Process	Etched
<u>Lead-</u> <u>Frame</u>	Lead-lock	No
	Part Number	101393765
	Lead Plating	Matte Sn
	Strip Size	80x250mm
	Strip Density	UDLF
Bond Wire	Material	Au
	Part Number	3230
<u>Die Attach</u>	Conductive	Yes
MC	Part Number	G631HQ
	Package Type	LQFP
<u>PKG</u>	Pin/Ball Count	100
	PKG width/size	14x14x1.4mm



Manufacturing Information

Assembly Lot No.					
ANAP244500075.000					
ANAP244500076.000					
ANAP244500077.000					

Result	✓ Pass	Fail	
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58U83 in 100L LQFP 14x14x1.4mm assembled at ANAP pass Reliability test conducted at MPHL rel lab. This package is qualified Moisture/Reflow Sensitivity Classification Level 3 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

	PACKAGE QUALIF	CATIO	N RE	POR	Γ	
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Precondition Prior Perform Reliability Tests (At MSL Level 3)	Electrical Test : 25°C D10I_UC 85°C D10I_UC	JESD22- A113, JIP/ IPC/JEDE C J-STD- 020E	231 per lot	Lot 1 0/231 Lot 2 0/231 Lot 3	Pass Pass Pass	Good Devices
	Bake 150°C, 24 hrs System: HERAEUS		231 per lot			
	Moisture Soak 192h(30°C/60%RH) System: VOTSCH VC4034		231 per lot			
	Reflow 3x Convection-Reflow 265°C max System: Mancorp CR.5000F	_	231 per lot	Lot 1 0/231 Lot 2 0/231 Lot 3 0/231	Pass Pass Pass	
	Electrical Test: 25°C D10I_UC 85°C D10I_UC	-	231 per lot	Lot 1 0/231 Lot 2 0/231	Pass Pass	
				Lot 3 0/231	Pass	

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 500 hrs System: HERAEUS	JESD22- A103	45 units 1 lot	Lot 1 0/45 Lot 2	Pass Pass	
	Electrical Test: 25°C D10I_UC 85°C D10I_UC			0/45 Lot 3 0/45	Pass	
HAST	Stress Condition: (Standard) 130°C, 85%RH, 96 hrs. VOLTS=3.3 System: HIRAYAMA HASTEST PC-422R8	JESD22- A110	77 units per lot	Lot 1 0/77 Lot 2 0/77	Pass Pass	Parts had been pre-conditioned at 260°C
	Electrical Test: 25°C D10I_UC 85°C D10I_UC			Lot 3 0/77	Pass	
UNBIASED HAS	T Stress Condition: (Standard) 130°C, 85%RH, 96 hrs. System: HIRAYAMA HASTEST PC-422R8	JESD22- A118	77 units per lot	0/77	Pass Pass	Parts had been pre-conditioned at 260°C
	Electrical Test: 25°C D10I_UC			Lot 3 0/77	Pass	

	PACKAGE QUAL	LIFICAT	ION I	REPORT	Γ	
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Temp Cycle	Stress Condition: (Standard) - 65°C/150°C, 500 Cycles System: Votsch VTS²7012 Electrical Test: 85°C D10I_UC	JESD22- A104	77 units per lot	Lot 1 0/77 Lot 2 0/77 Lot 3 0/77	Pass Pass Pass	Parts had been pre- conditioned at 260°C
	Wire Bond Pull WBP	Mil. Std. 883- 2011	5 units, 30 bonds 1 lot	Lot 1 0/30	Pass	
Wire Bond Pull WBP, 0 Hour		Mil. Std. 883- 2011	5 units, 30 bonds 1 lot	Lot 1 0/30	Pass	
Wire Bond Shear WBS, 0Hour		CDF-AEC- Q100-001	5 units, 30 bonds 1 lot	Lot 1 0/30	Pass	
Standard Pb-free Solderability	>95% lead coverage	J-STD-002E	22 units 1 lot	0/22	Pass	

CCB 6779 Pre and Post Change Summary PCN #:CAAN-02PELF720



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LEAD FRAME COMPARISON



